

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10790711	FUJINAWA ET AL.
	Examiner	Art Unit
	Kaplan, Benjamin A	2109

SEARCHED

Class	Subclass	Date	Examiner
380	45,281		
713	193		
726	27,30		

SEARCH NOTES

Search Notes	Date	Examiner

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner